

ISSUE CLASSIFICATION	
Class	Subclass

PATENT NUMBER

U.S. UTILITY Patent Application

JC #16
JC 888

O.I.P.E.

PATENT DATE

FA
SCANNED TK4 Q.A. 15

APPLICATION NO. 09/881445	CONT/PRIOR D F	CLASS 438	SUBCLASS 14	ART UNIT 2818	EXAMINER R. BERRY
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TITLE **APPLICANTS**

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Layer-thickness detection methods and apparatus for wafers and the like, and polishing apparatus comprising same.

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PTO-2040
12/89

ISSUING CLASSIFICATION									
ORIGINAL			CROSS REFERENCE(S)						
CLASS	SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
INTERNATIONAL CLASSIFICATION									

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<input type="checkbox"/> TERMINAL DISCLAIMER	DRAWINGS		CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims
<input type="checkbox"/> The term of this patent subsequent to _____ (date) has been disclaimed.			NOTICE OF ALLOWANCE MAILED	
	(Assistant Examiner)	(Date)		
<input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S Patent. No. _____ _____			ISSUE FEE	
	(Primary Examiner)	(Date)	Amount Due	Date Paid
<input type="checkbox"/> The terminal ____months of this patent have been disclaimed.			ISSUE BATCH NUMBER	
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